

April 1988 Revised September 2000

74F377

Octal D-Type Flip-Flop with Clock Enable

General Description

The 74F377 has eight edge-triggered, D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) input loads all flip-flops simultaneously, when the Clock Enable $(\overline{\text{CE}})$ is LOW.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output. The $\overline{\text{CE}}$ input must be stable only one setup time prior to the LOW-to-HIGH clock transition for predictable operation.

Features

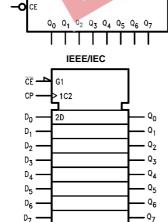
- Ideal for addressable register applications
- Clock enable for address and data synchronization applications
- Eight edge-triggered D-type flip-flops
- Buffered common clock
- See 74F273 for master reset version
- See 74F373 for transparent latch version
- See 74F374 for 3-STATE version

Ordering Code:

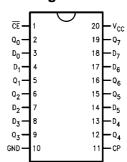
Order Number	Package Number	Package Description
74F377SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F377SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F377PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP) JEDEC MS-001 0 300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" tot he ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I _{IH} /I _{IL}	
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}	
D ₀ –D ₇	Data Inputs	1.0/1.0	20 μA/-0.6 mA	
CE	Clock Enable (Active LOW)	1.0/1.0	20 μA/-0.6 mA	
CP	Clock Pulse Input	1.0/1.0	20 μA/-0.6 mA	
Q ₀ -Q ₇	Data Outputs	50/33.3	-1 mA/20 mA	

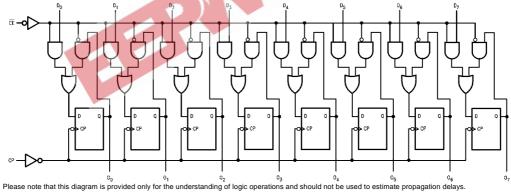
Mode Select-Function Table

		Output			
Operating Mode	СР	CP CE D _n		Q _n	
Load "1"	~	I	h	Н	
Load "0"	~	I	I	L	
Hold	~	h	X	No Change	
(Do Nothing)	Х	Н	X	No Change	

- H = HIGH Voltage Level
 h = HIGH Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition
 L = LOW Voltage Level
 I = LOW Voltage Level one setup time prior to the LOW-to-HIGH Clock Transition
 X = Immaterial

 T = LOW-to-HIGH Clock Transition

Logic Diagram



Absolute Maximum Ratings(Note 1)

-65°C to +150°C

Storage Temperature Ambient Temperature under Bias -55°C to +125°C Junction Temperature under Bias -55°C to +150°C

V_{CC} Pin Potential to Ground Pin -0.5V to +7.0V Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with $V_{CC} = 0V$)

–0.5V to $V_{\mbox{\footnotesize CC}}$ Standard Output 3-STATE Output -0.5V to +5.5V

Current Applied to Output

twice the rated I_{OL} (mA) in LOW State (Max) ESD Last Passing Voltage (Min)

Recommended Operating Conditions

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

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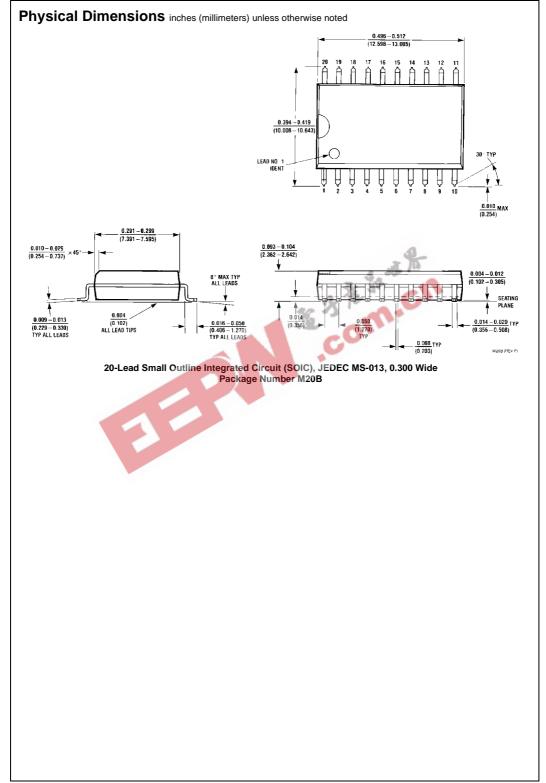
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

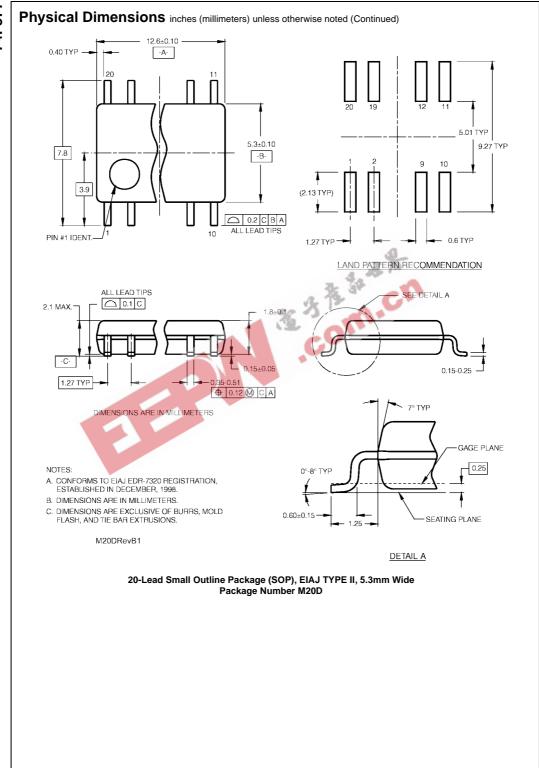
DC Electrical Characteristics

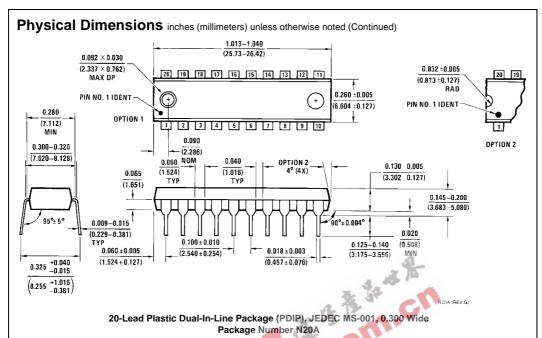
Symbol	Parameter	Min	Тур	Max	Units	V _{CC}	Conditions		
V _{IH}	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal		
V _{IL}	Input LOW Voltage			0.8	V		Recognized as a LOW Signal		
V _{CD}	Input Clamp Diode Voltage			-1.2	V	Min	I _{IN} = -18 mA		
V _{OH}	Output HIGH 10% V _{CC}	2.5			V	Min	I _{OH} = -1 mA		
	Voltage 5% V _{CC}	2.7		-	O. J.	IVIII I	$I_{OH} = -1 \text{ mA}$		
V _{OL}	Output LOW Voltage 10% V _{CC}	, T		0.5	V	Min	I _{OL} = 20 mA		
I _{IH}	Input HIGH Current		, ,	5.0	μΑ	Max	V _{IN} = 2.7V		
I _{BVI}	Input HIGH Current	. 1		7.0	μА	Max	V _{IN} = 7.0V		
	Breakdown Test			7.0	μА	IVIAX	V _{IN} = 7.0 V		
I _{IL}	Input LOW Current			-0.6	mA	Max	$V_{IN} = 0.5V$		
Ios	Output Short-Circuit Current	-60		-150	mA	Max	$V_{OUT} = 0V$		
I _{CEX}	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC}$		
V _{ID} Inpu	Input Leakage	4.75			٧	0.0	$I_{ID} = 1.9 \mu\text{A}$		
	Test	4.73					All Other Pins Grounded		
I _{OD}	Output Leakage			3.75		0.0	V _{IOD} = 150 mV		
	Circuit Current			3.75	μА	0.0	All Other Pins Grounded		
I _{CCH}	Power Supply Current		35	46	mA	Max	CP =		
I _{CCL}			44	56	IIIA	IVIAX	$D_n = \overline{MR} = HIGH$		

AC E	ectrical Character	istics							
Symbol	Parameter		$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -55$ °C to +125°C $V_{CC} = +5.0V$ $C_L = 50$ pF		$T_A = 0$ °C to $+70$ °C $V_{CC} = +5.0V$ $C_L = 50$ pF	
		Min	Тур	Max	Min	Max	Min	Max	
f _{MAX}	Maximum Clock Frequency	130			85		105		MHz
t _{PLH}	Propagation Delay	3.0		7.0	2.0	8.5	2.5	7.5	no
t _{PHL}	CP to Q _n	4.0		9.0	3.0	10.5	3.5	9.0	ns

AC Operating Requirements







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